SONY

CXD1176Q

8-bit 20MSPS Video A/D Converter with Clamp Function

Description

The CXD1176Q is an 8-bit CMOS A/D converter for video use that features a sync clamp function. The adoption of a 2 step-parallel method realizes low power consumption and a maximum conversion speed of 20MSPS.

Features

- Resolution power: 8-bit ± 1/2LSB (DL)
- Maximum sampling frequency: 20MSPS
- Low power consumption: 60mW (at 20MSPS typ.) (Reference current excluded)
- Built-in sync type clamp function
- Built-in monostable multivibrator for clamp pulse generation
- Built-in sync pulse polarity selection function
- Clamp pulse direct input possible
- Built-in clamp ON/OFF function
- Built-in reference voltage self-bias circuit
- Input CMOS compatible
- 3-state TTL compatible output
- Single 5V power supply
- Low input capacity: 11pF
- Reference impedance: 330Ω (typ.)

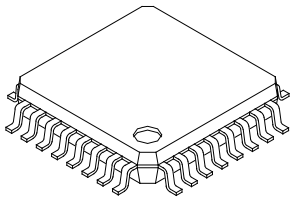
Applications

TV and VCR digital systems and a wide range of applications where high-speed A/D conversion is required.

Structure

Silicon gate CMOS IC

32 pin QFP (Plastic)



Absolute Maximum Ratings (Ta = 25°C)

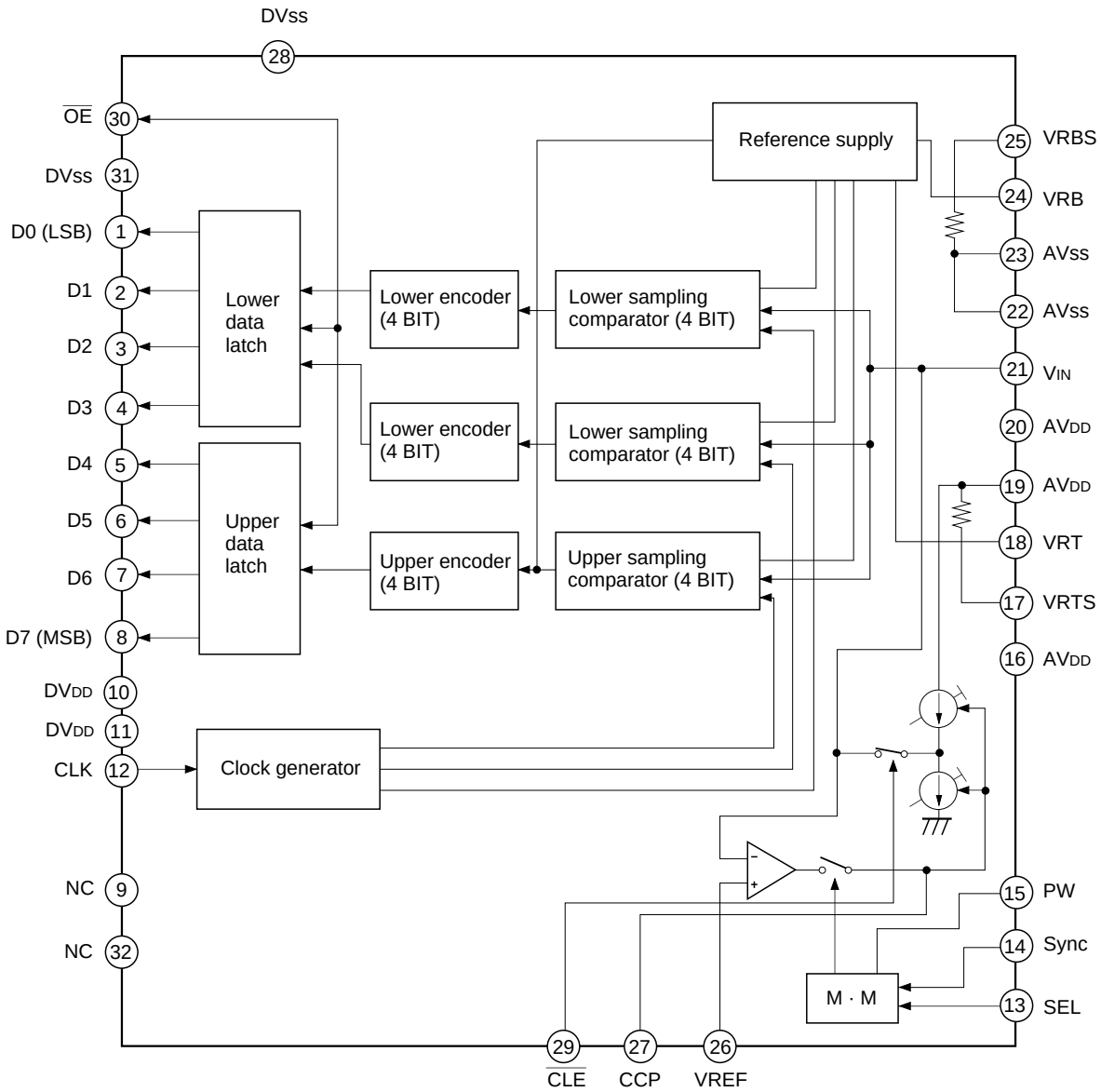
• Supply voltage	V_{DD}	7	V
• Reference voltage	V_{RT}, V_{RB}	V_{DD} + 0.5 to V_{SS} – 0.5	V
• Input voltage (Analog)	V_{IN}	V_{DD} + 0.5 to V_{SS} – 0.5	V
• Input voltage (Digital)	V_I	V_{DD} + 0.5 to V_{SS} – 0.5	V
• Output voltage (Digital)	V_O	V_{DD} + 0.5 to V_{SS} – 0.5	V
• Storage temperature	Tstg	–55 to +150	°C

Recommended Operating Conditions

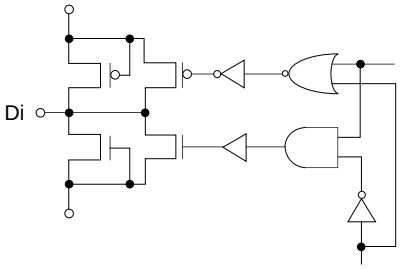
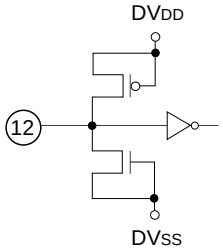
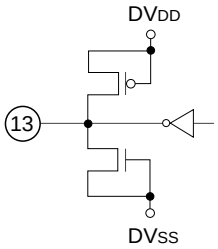
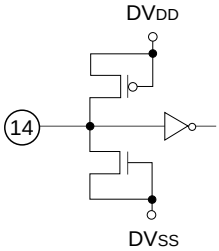
• Supply voltage	AV_{DD}, AV_{SS}	4.75 to 5.25	V
	DV_{DD}, DV_{SS}		
	$\lvert DV_{SS} - AV_{SS} \rvert$	0 to 100	mV
• Reference input voltage			
	V_{RB}	0 to	V
	V_{RT}	to 2.7	V
• Analog input	V_{IN}	1.8Vp-p above	
• Clock pulse width			
	Tpw_1, Tpw_0	22.5ns (min) to 1.1µs (max)	
• Operating ambient temperature			
	Topr	–40 to +85	°C

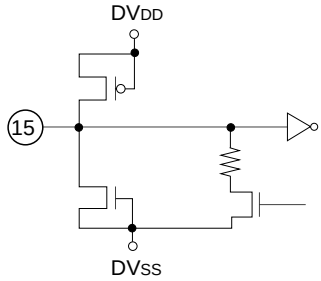
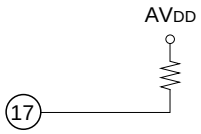
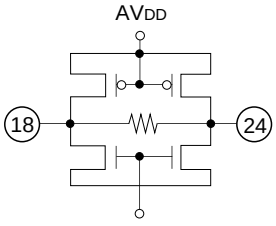
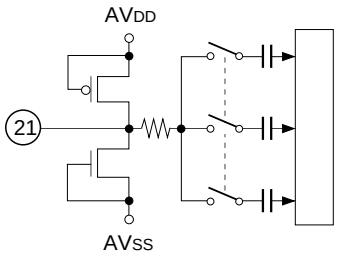
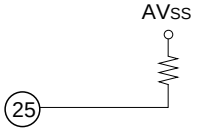
E90167H78-PS

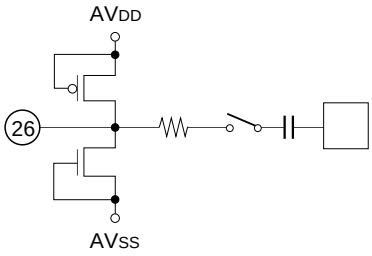
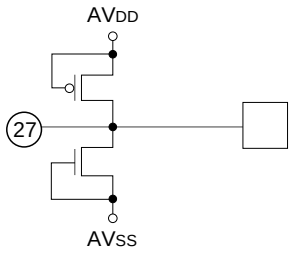
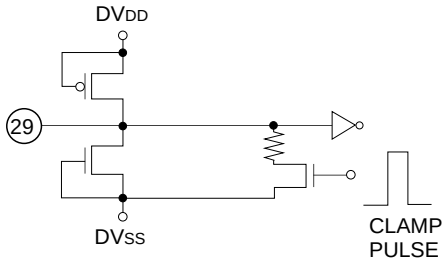
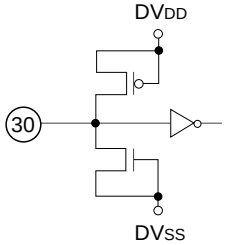
Block Diagram and Pin Configuration



Pin Description

Pin No.	Symbol	Equivalent circuit	Description
1 to 8	D0 to D7		D0 (LSB) to D7 (MSB) output
9, 32	NC		NC pin
10, 11	DV_{DD}		Digital +5V
12	CLK		Clock input
13	SEL		When SEL is at low, with the falling edge of Pin 14 (sync) as trigger, the monostable multivibrator generates clamp pulses. When SEL is at high, with the rising edge of Pin 14 (sync) as trigger, it generates clamp pulses.
14	Sync		Trigger pulse input to the monostable multivibrator. Trigger polarity can be selected through Pin 13 (SEL).

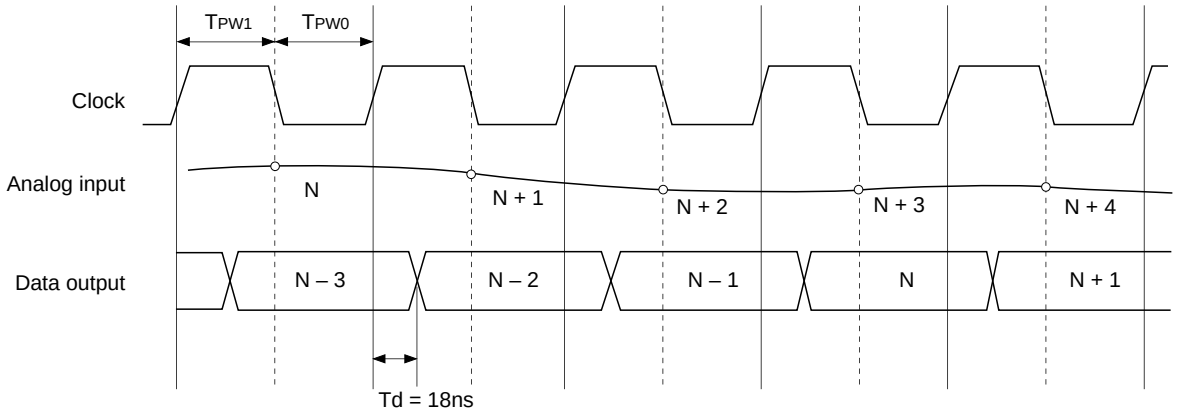
Pin No.	Symbol	Equivalent circuit	Description
15	PW		When a clamp pulse is generated at the monostable multivibrator, the pulse width is determined by the external R and C. When the clamp pulse is directry input, it is input to Pin 15 (PW). The signal voltage of the low period is clamped. (Here, Pin 14 (sync) is fixed to either low or high.)
16, 19, 20	AVDD		Analog +5V
17	VRTS		When shorted with VRT, generates approx. +2.6V.
18	VRT		Reference voltage (top)
24	VRB		Reference voltage (bottom)
21	VIN		Analog input
22, 23	AVSS		Analog ground
25	VRBS		When shorted with VRB, generates approx. +0.5V.

Pin No.	Symbol	Equivalent circuit	Description
26	VREF		Clamp reference voltage input. Clamps to provide a clamp period input signal equal to the reference voltage.
27	CCP		Integrates the voltage for clamp control. CCP and V_{IN} voltage changes are in positive phase.
28, 31	DVSS		Digital ground.
29	$\overline{CLE}$		When $\overline{CLE}$ is at low, clamp function is activated. When $\overline{CLE}$ is at high, clamp function is OFF and only the usual A/D converter function is active. By connecting $\overline{CLE}$ pin to DV_{DD} via a several hundred Ω resistance, the clamp pulse can be tested.
30	$\overline{OE}$		When $\overline{OE}$ is at low, Data is output. When $\overline{OE}$ ia at high, D0 to D7 pins turn to high impedance.

Digital Output

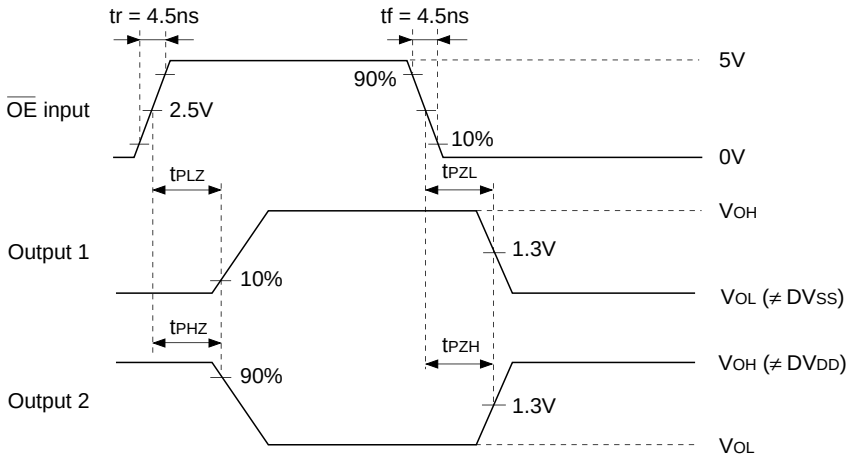
Correspondence between the analog input voltage and the digital output code is indicated in the chart below.

Input signal voltage	Step	Digital output code MSB LSB
V_{RT}	0	1 1 1 1 1 1 1 1
⋮	⋮	⋮
	127	1 0 0 0 0 0 0 0
	128	0 1 1 1 1 1 1 1
	⋮	⋮
V_{RB}	255	0 0 0 0 0 0 0 0



○ : Points where analog signals are sampled.

Timing Chart. I



Timing Chart. II

Electrical Characteristics

Analog characteristics (Fc = 20MSPS, V_{DD} = 5V, V_{RB} = 0.5V, V_{RT} = 2.5V, Ta = 25°C)

Item	Symbol	Conditions		Min.	Typ.	Max.	Unit
Conversion speed	Fc	V_{DD} = 4.75 to 5.25V Ta = –40 to +85°C V_{IN} = 0.5 to 2.5V f_{IN} = 1kHz ramp		0.5		20	MSPS
Analog input band width (–1dB)	BW	Envelope			18		MHz
Offset voltage*1	E_{OT}	Potential difference to VRT		–60	–40	–20	mV
	E_{OB}	Potential difference to VRB		+20	+40	+60	
Integral non-linearity error	E_L	End point			+0.5	+1.3	LSB
Differential non-linearity error	E_D				±0.3	±0.5	
Differential gain error	DG	NTSC 40 IRE mod ramp Fc = 14.3MSPS			1.0		%
Differential phase error	DP				0.5		deg
Aperture jitter	taj				30		ps
Sampling delay	tsd				4		ns
Clamp offset voltage*2	Eoc	V_{IN} = DC, PWS = 3µs	V_{REF} = 0.5V	0	+20	+40	mV
			V_{REF} = 2.5V	–50	–30	–10	
Clamp pulse width (Sync pin input)	tcpw	C = 100pF, R = 130kΩ (15PIN)		1.75	2.75	3.75	µs
Clamp pulse delay	tcpd				25		ns

*1 The offset voltage EOB is a potential difference between VRB and a point of position where the voltage drops equivalent to 1/2 LSB of the voltage when the output data changes from “00000000” to “00000001”. EOT is a potential difference between VRT and a potential of point where the voltage rises equivalent to 1/2LSB of the voltage when the output data changes from “11111111” to “11111110”.

*2 Clamp offset voltage varies individually. When using with R, G, B 3 channels, color sliding may be generated.

DC characteristics (Fc = 20MSPS, V_{DD} = 5V, V_{RB} = 0.5V, V_{RT} = 2.5V, Ta = 25°C)

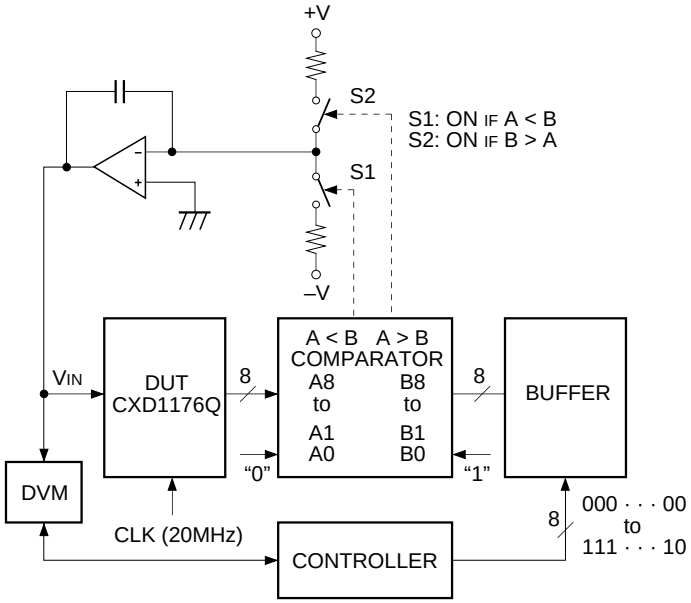
Item	Symbol	Conditions		Min.	Typ.	Max.	Unit
Supply current	I_{DD}	Fc = 20MSPS NTSC ramp wave input			12	18	mA
Reference pin current	I_{REF}			4.5	6.6	8.7	mA
Analog input capacitance	C_{IN}	V_{IN} = 1.5V + 0.07Vrms			11		pF
Reference resistance (V_{RT} to V_{RB})	R_{REF}			230	300	450	Ω
Self-bias I	VRB_1	VRB and VRBS are shorted VRT and VRTS are shorted		0.48	0.52	0.56	V
	VRT_1 to VRB_1			1.96	2.08	2.22	
Self-bias II	VRT_2	VRB = AGND VRT and VRTS are shorted			2.32		V
Digital input voltage	V_{IH}	V_{DD} = 4.75 to 5.25V Ta = –40 to +85°C		4.0			V
	V_{IL}					1.0	
Digital input current	I_{IH}	V_{DD} = max	$V_{IH} = V_{DD}$			5	µA
	I_{IL}		V_{IL} = 0V			5	
Digital output current	I_{OH}	$\overline{OE} = V_{SS}$ V_{DD} = min	$V_{OH} = V_{DD}$ – 0.5V	–1.1			mA
	I_{OL}		V_{OL} = 0.4V	3.7			
	I_{OZH}	$\overline{OE} = V_{DD}$ V_{DD} = max	$V_{OH} = V_{DD}$			16	µA
	I_{OZL}		V_{OL} = 0V			16	

Timing (Fc = 20MSPS, V_{DD} = 4.75 to 5.25V, V_{RB} = 0.5V, V_{RT} = 2.5V, Ta = –40 to +85°C)

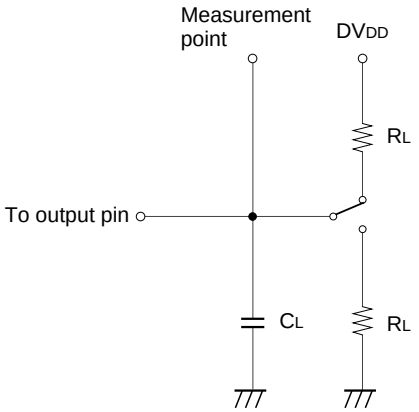
Item	Symbol	Conditions	Min.	Typ.	Max.	Unit
Output data delay	T_{DL}	with TTL 1 gate and 10pF load		18	30	ns
Tri-state output enable time	t_{PZH} t_{PZL}	R_L = 1kΩ, C_L = 20pF $\overline{OE}$ = 3V → 0V	2.5	6	10	ns
Tri-state output disable time	t_{PHZ} t_{PLZ}	R_L = 1kΩ, C_L = 20pF $\overline{OE}$ = 0V → 3V	8	18	30	ns

Electrical Characteristics Measurement Circuit

Integral non-linearity error
Differential non-linearity error } **measurement circuit**
Offset voltage

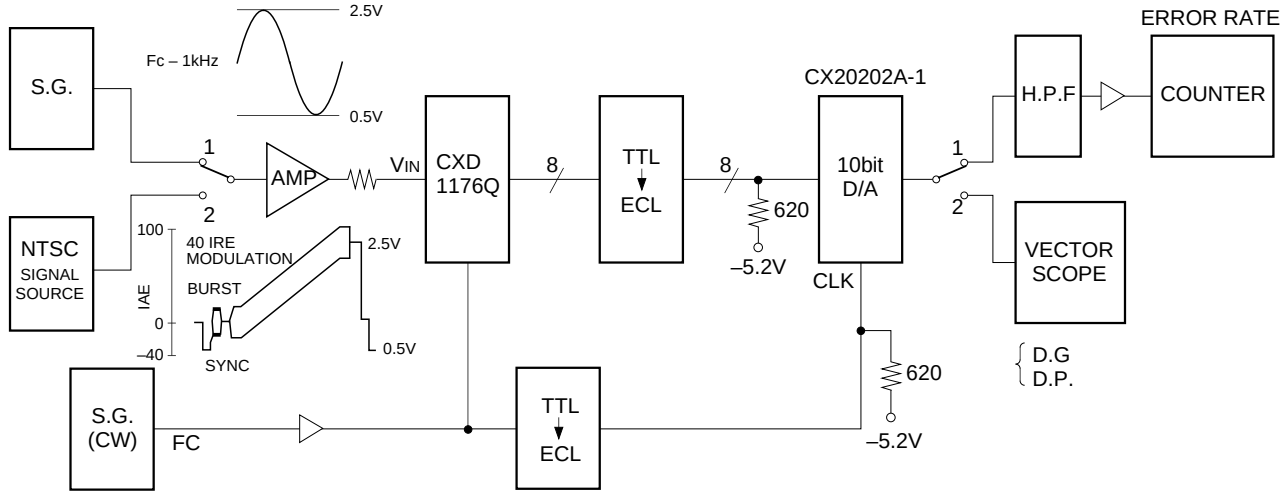


Tri-state output measurement circuit

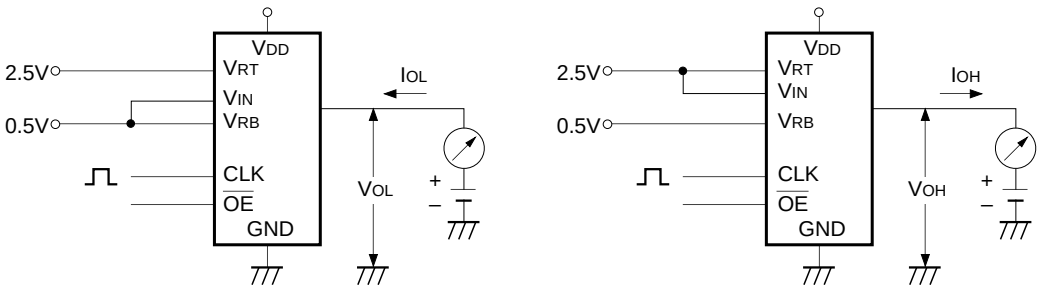


Note) CL includes capacitance of the probe and others.

Maximum operational speed
Differential gain error } **measurement circuit**
Differential phase error

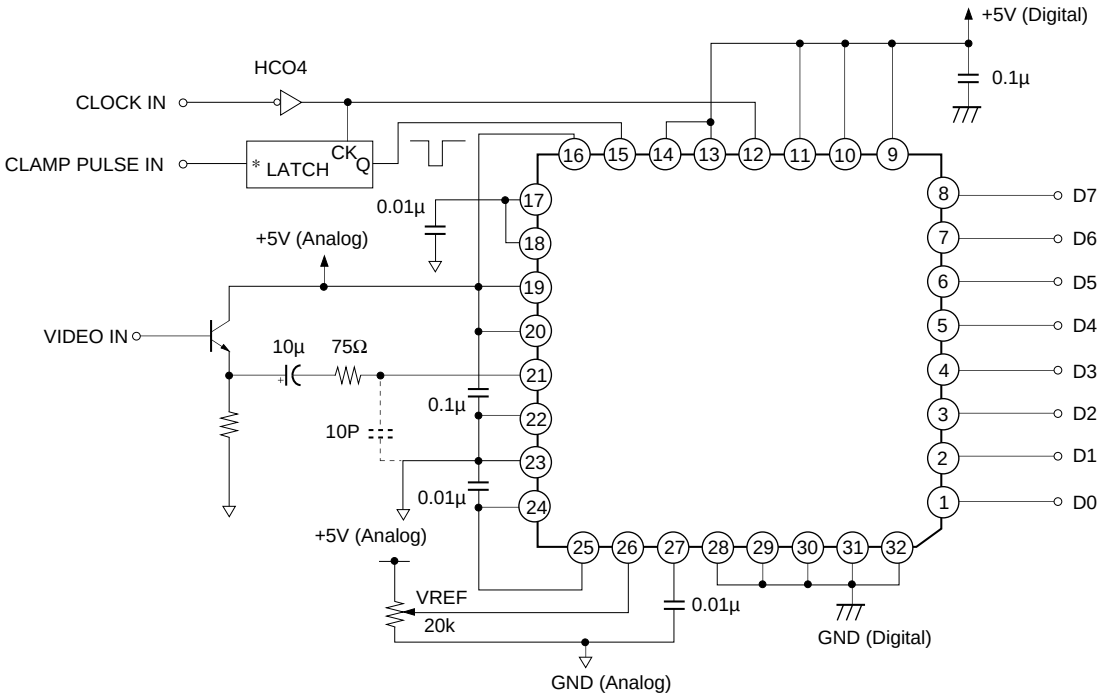


Digital output current measurement circuit

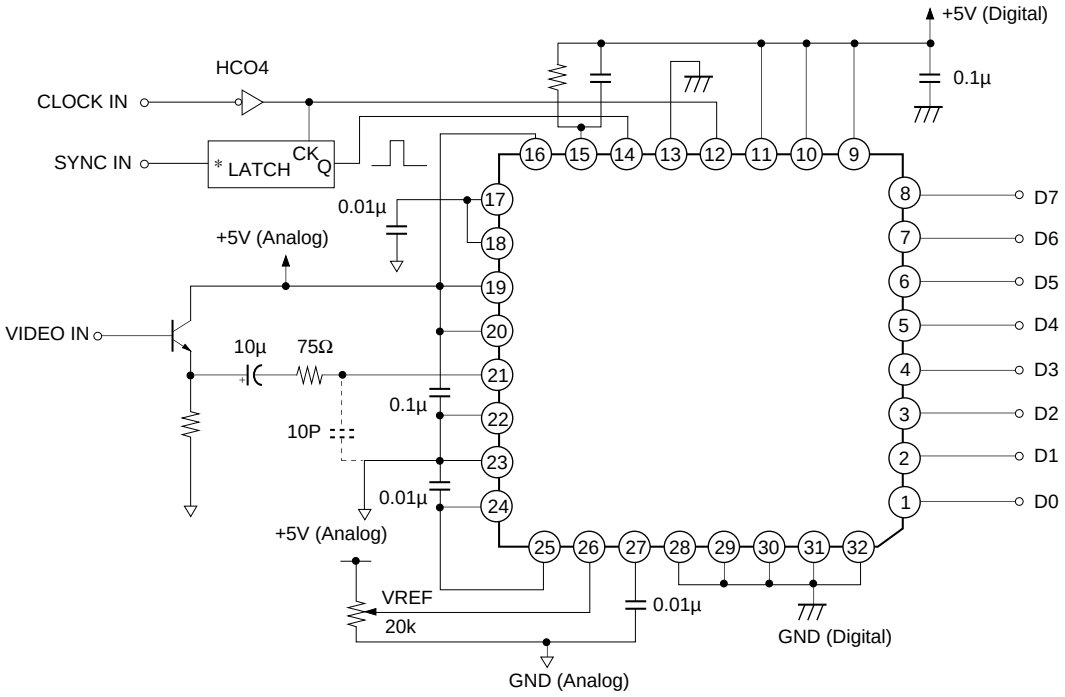


Application Circuit

(1) Case where clamp pulse is directry input (self-bias used)

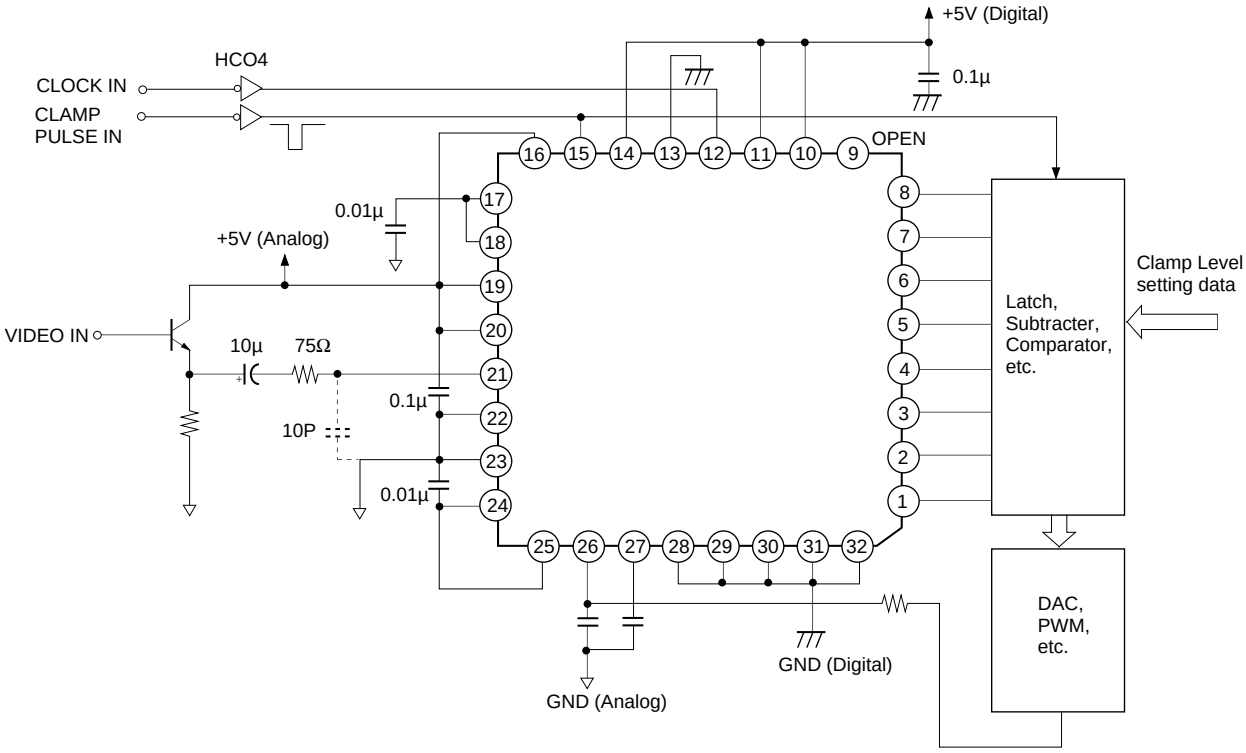


(2) Example where pedestal clamp is executed by sync pulse (self-bias used)

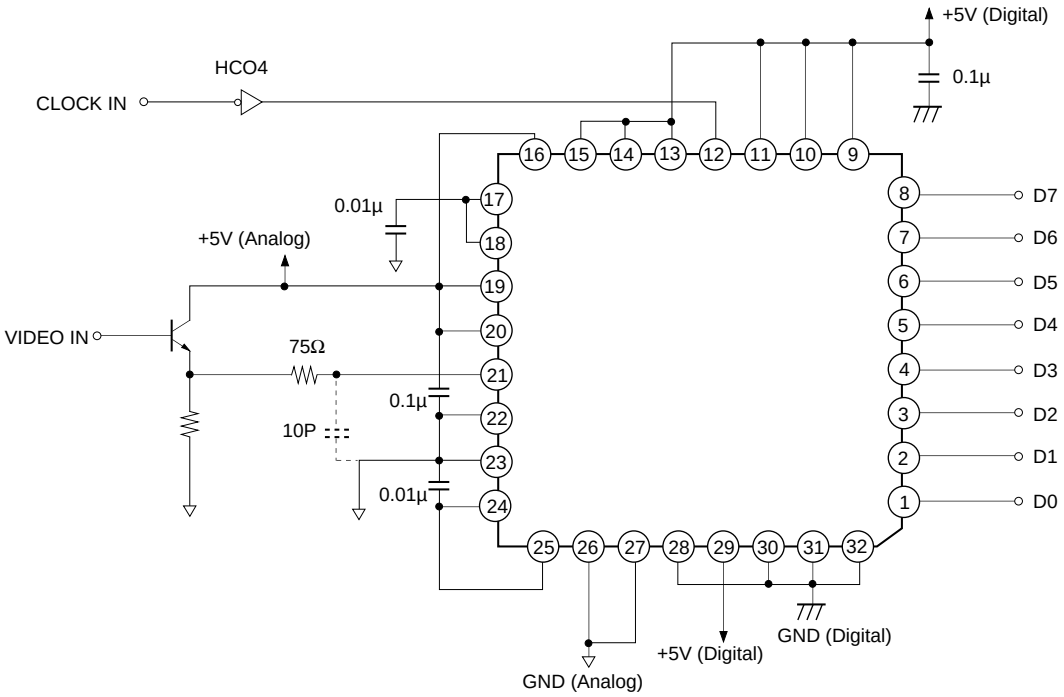


* The clamp pulse is latched by the ADC sampling clock, but that is not necessary for clamp basic operation. However, slight beat may be generated as vertical sag according to the relation between the sampling frequency and clamp pulse frequency.
At such time, the latch circuit is effective. (See Notes on Operation (5).)

(3) Digital clamp (self-bias used)



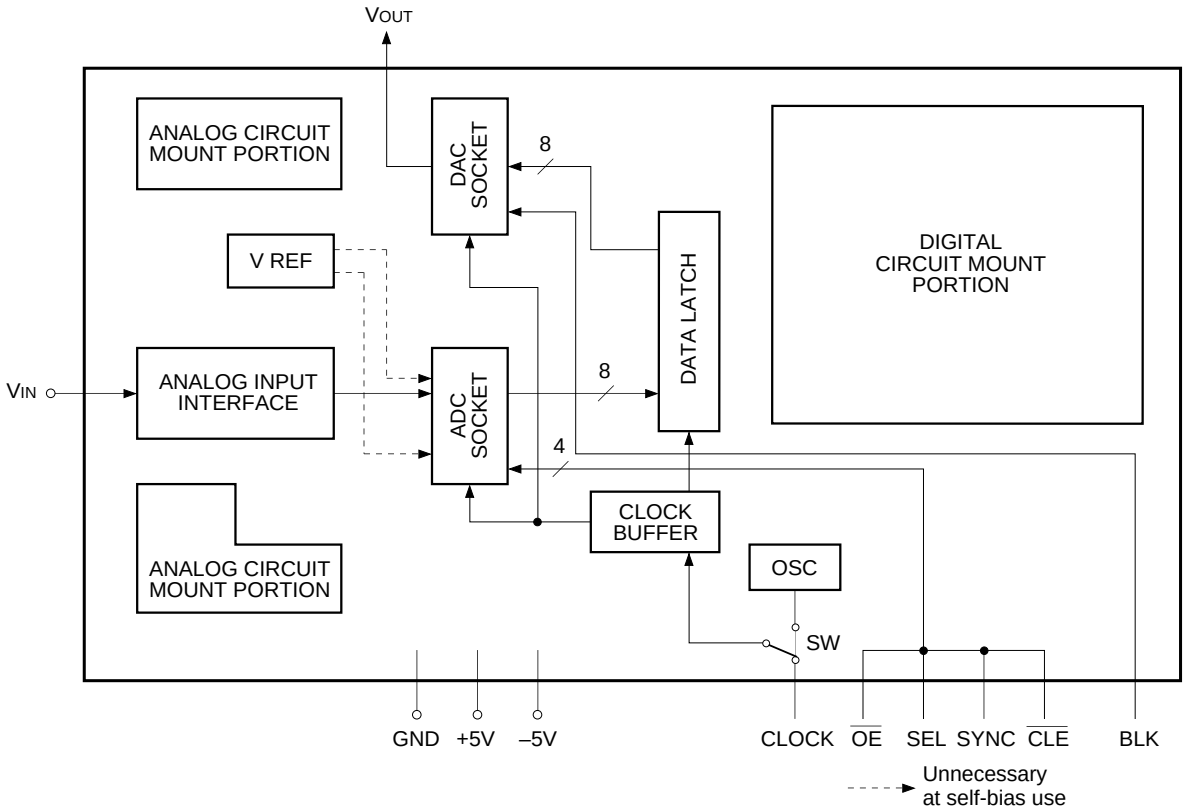
(4) When clamp is not used (self-bias used)



8-bit 20MSPS ADC and DAC Evaluation Board

Evaluation boards are available for the high speed, low power consumption CMOS converters, CXD1176Q (8-bit 20MHz A/D) and CXD1171M (8-bit 40MHz D/A).
The evaluation board is composed of a main board common to either type, to which is added sub board CXD1176Q or sub board CXD1171M. The junction is made through a socket.
To the main board are mounted an input interface, clock buffer and latch. To each of the sub boards is mounted CXD1176Q and CXD1171M respectively. Those IC's are mounted according to recommended print patterns designed to provide maximum performance to the A/D and D/A converters.

Block Diagram



Characteristics

- Resolution 8bit
- Maximum conversion rate 20MHz
- Digital input level CMOS level
- Supply voltage ±5.0V (Single +5V power supply possible at self bias use)

Supply voltage

Item	Min.	Typ.	Max.	Unit
+5V –5V			150 20	mA

Clock input

CMOS compatible

Pulse width T_{CW1} 22.5ns (min)

T_{CW0} 22.5ns (min)

Analog Output (CXD1171M) (R_L > 10kΩ)

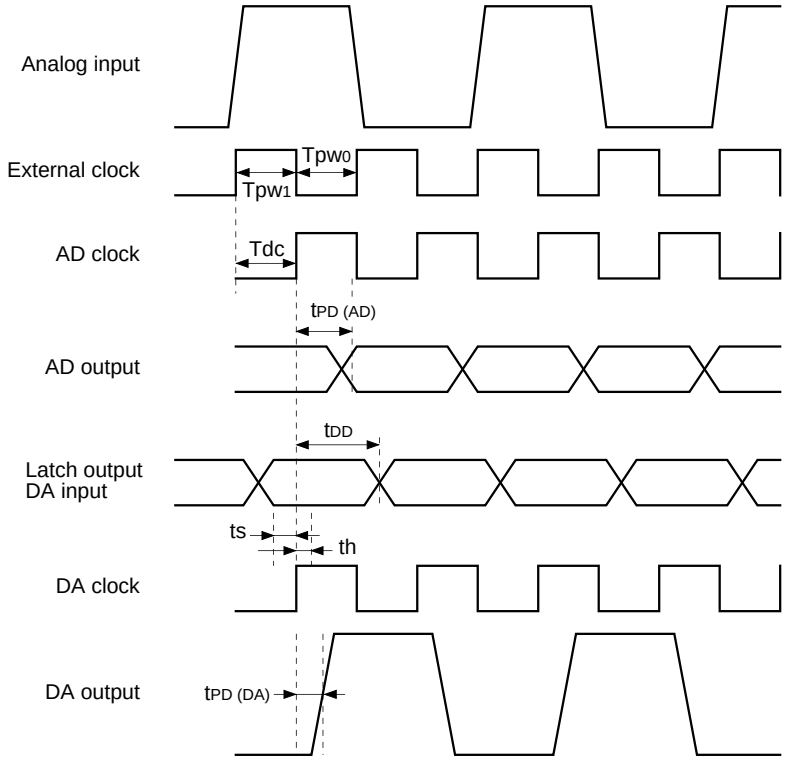
Item	Min.	Typ.	Max.	Unit
Analog output	1.9	2.0	2.1	V

Output Format (CXD1176Q)

The table shows the output format of AD Converter.

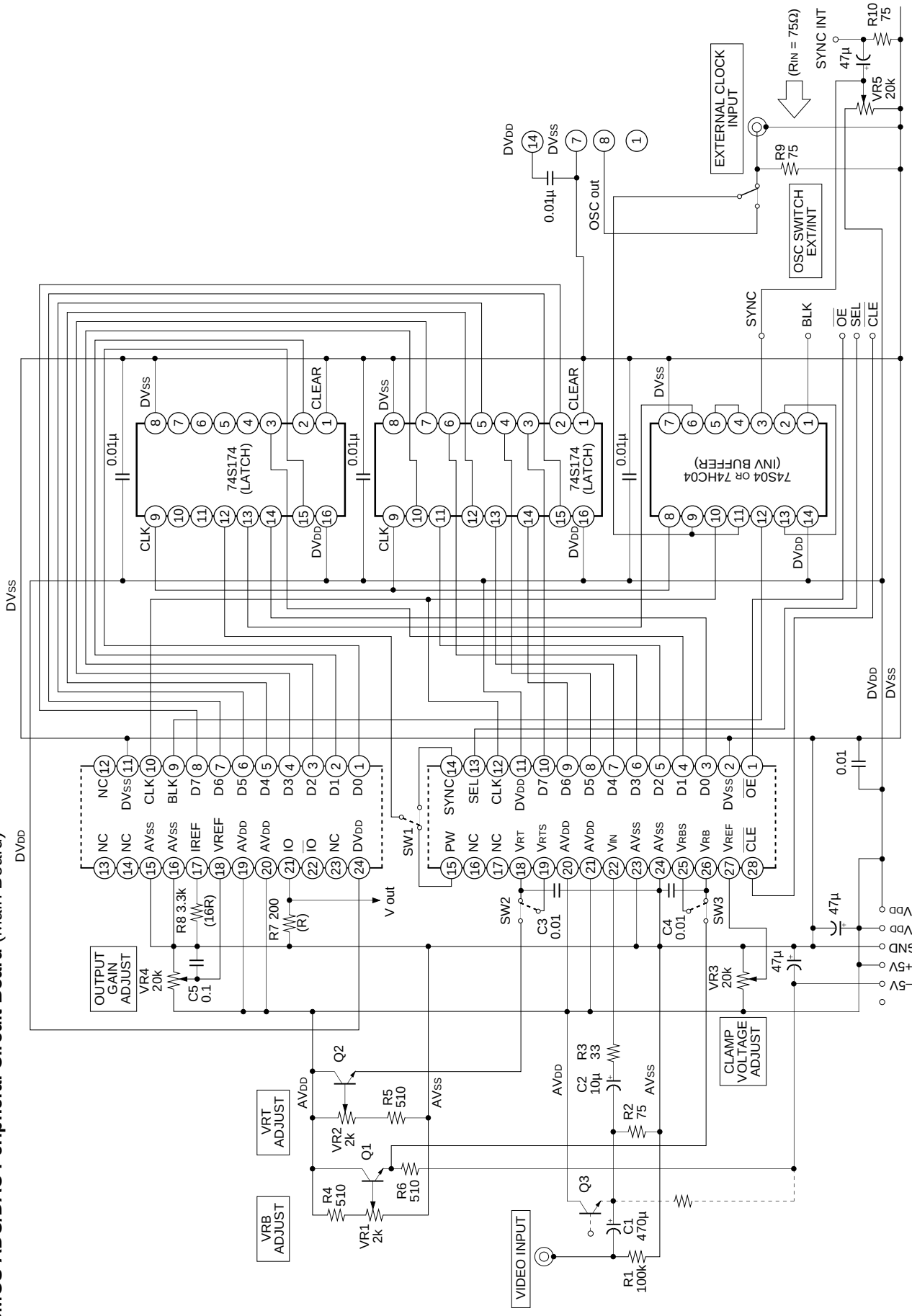
Analog input voltage	Step	Digital output code MSB LSB
V_{RT}	0	1 1 1 1 1 1 1 1
⋮	⋮	⋮
	127	1 0 0 0 0 0 0 0
	128	0 1 1 1 1 1 1 1
⋮	⋮	⋮
V_{RB}	255	0 0 0 0 0 0 0 0

Timing Chart

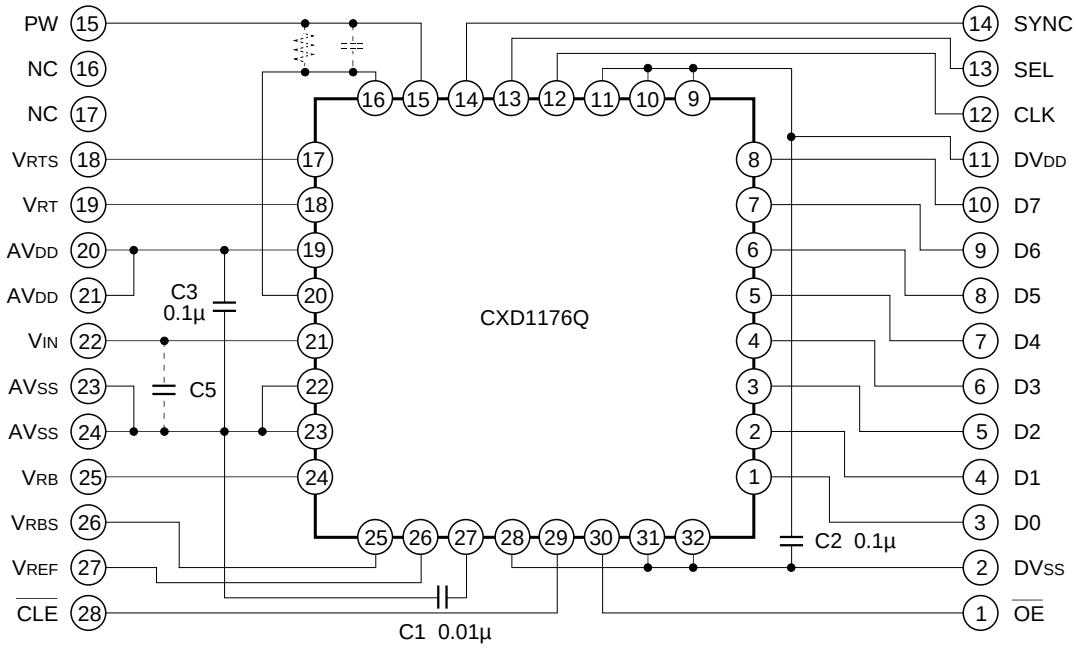


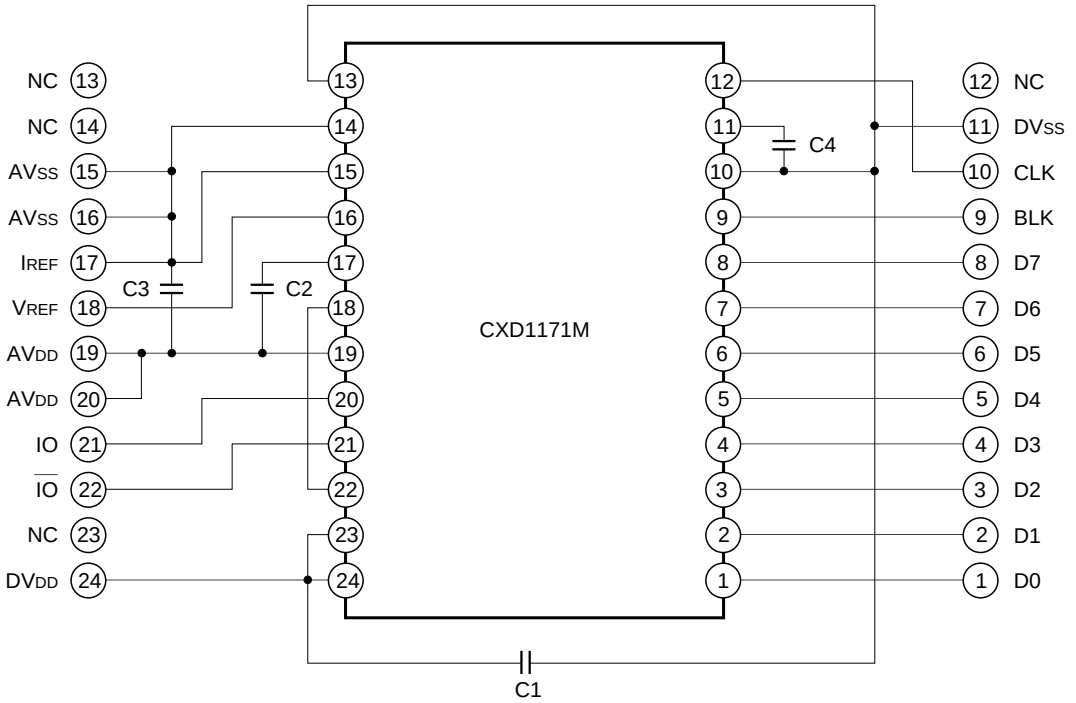
Item	Symbol	Min.	Typ.	Max.	Unit
Clock High time	T_{PW1}	25			ns
Clock Low time	T_{PW0}	25			ns
Clock Delay	Tdc			24	ns
Data delay AD	$t_{PD\ (AD)}$		18	30	ns
Data delay (latch)	t_{DD}			5	ns
Set up time	t_S	5			ns
Hold time	th	10			ns
Data delay DA	$t_{PD\ (DA)}$		10		ns

CMOS ADC/DAC Peripheral Circuit Board (Main Board)



CMOS ADC/DAC Peripheral Circuit Board (Sub Board)





List of Parts

resistance

R1	100kΩ
R2	75Ω
R3	75Ω
R4	510Ω
R5	510Ω
R6	510Ω
R7	R = 200Ω
R8	18R ≈ 3.3kΩ
R9	75Ω
R10	75Ω
VR1	2kΩ
VR2	2kΩ
VR3	20kΩ
VR4	20kΩ
VR5	20kΩ

capacitance

C1	470µF/6.3V (chemical)
C2	10µF/16V (chemical)
C3	0.01µF
C4	0.01µF
C5	0.1µF
C6	0.1µF
C7	0.1µF
C8	0.1µF
C9	0.1µF
C10	0.1µF
C11	47µF/10V (chemical)
C12	47µF/10V (chemical)
C13	47µF/10V (chemical)
C14	0.1µF

transistor

Q1	2SC2785
Q2	2SC2785
Q3	2SC2785

IC

IC1	74S174
IC2	74S174
IC3	74S04

oscillator

OSC

others

connector	BNC071
SW	AT1D2M3

Adjustment

1. Vref adjustment (VR1, VR2)
   Adjustment of A/D converter reference voltage. VRB is adjusted through VR1 and VRT through VR2. When self-bias is used, there is no need for adjustment. Reference voltage is set through self-bias delivery.

2. Setting of clamp reference voltage (VR3)
   Clamp reference voltage is set.

3. DAC output full-scale adjustment (VR4)
   Full-scale voltage of D/A converter output is adjusted at the PCB shipment, the full-scale voltage is adjusted to approx. 2V.

4. Sync (clamp) pulse interface (VR5)
   This adjustment enables interface with the signal generator and others at the PCB shipment, adjustment is performed to obtain a threshold of approx. 2.5V to an H sync of 0 to 5V.

5. $\overline{OE}$, SEL, Sync, BLK, $\overline{CLE}$, Sync INT
   The following pins are set on the main board: $\overline{OE}$, SEL, Sync, $\overline{CLE}$, Sync INT (CXD1176Q) and BLK (CXD1171M). For the pins function, refer to the specifications. The difference between Sync pin and Sync INT pin is that you input a horizontal synchronizing signal above 3.5Vp-p Sync INT pin. The pulse threshold is set through VR5. For input through Sync pin, pulse is input at TTL or CMOS level. In this case cut off the junction line between Sync and Sync INT pin.
   At the PCB shipment the main board pins are set as follows.
   - $\overline{OE}$ ... Low (A/D output ON)
   - SEL ... Low (Pulse generated with Sync falling edge as trigger)
   - Sync ... Line junction with Sync INT pin
   - $\overline{CLE}$ ... Low (Clamp function ON)
   - BLK ... Low (Blanking OFF)

6. Clamp pulse input method
   One method, as shown in Application Circuit examples (1) and (2), is to directry input the clamp pulse. The other is to use the built-in monostable multivibrator. The method is selected through SW1. At the PCB shipment it is set to direct input. To use the built-in monostable multivibrator, it is necessary to mount on the CXD1176Q sub board, R and C that determine pulse width.
   (Ex. R = 130k, C = 100p, Tpw = 2.75µs Typ.)

Points on the PCB Pattern Layout

1. Set the layout not to have Digital current flow into Analog GND (Part 1). (For 1, See p. 21 Component side diagram.)

2. At CXD1176Q sub board, C_2 and C_3 capacitors serve the important role of bringing out CXD1176Q's full performance.
   There are over 0.1µF (ceramic) capacitors with good high frequency characteristics. Layout as close to the IC as possible.

3. Analog GND (AV_{SS}) and Digital GND (DV_{SS}) are on a common voltage and power source. Keeping ADC's DV_{SS} (Part 2) as close as possible to the voltage supply source will provide better results. That is, a layout where ADC is close to the voltage supply source, is recommended. (For 2, see p. 21 Component side diagram.)

4. ADC samples analog signals at the clock falling edge point. Accordingly clocks supplied to ADC should not have any jitter.

5. The PCB layout shows ADC and DAC's Analog GND independently from the voltage generating source. On this PCB, the layout aims at providing an independent evaluation of ADC and DAC, as much as possible. On the actual board, common use will not cause any problems.

Notes on Operation

1. Reference voltage
   Shorting V_{RT} and V_{RTS}, V_{RB} and V_{RBS} will activate the self-bias function that generates V_{RT} = 2.6V and V_{RB} = 0.5V. On the PCB, either self-bias or the external reference voltage can be selected depending on the junction method of the jumper line. At shipment from the factory, reference voltage is provided in self-bias. Also, to provide external reference voltage, adjust the dynamic range (V_{RT} – V_{RB}) to above 1.8Vp-p.

2. Clock input
   There are 2 modes for the PCB clock input
   1) Provided from the external signal generator. (External clock)
   2) Using the crystal oscillator (built-in clock driver). (Internal clock)

   The 2 modes are selected using the switch on the PCB.

3. The 2 Latch IC's (74S174) are not absolutely necessary for the evaluation of ADC and DAC. That is, operation will still be normal if ADC output data is directly input to DAC input. However, as ADC output data is hardly ever D/A converted without executing Digital signal processing, it was mounted to indicate an example layout of Digital signal processing IC.

4. When clamp is not used
   Turning $\overline{CLE}$ to H will set OFF the clamp function. In this case, the DC element is cut off by means of C_2 on the main board and DC voltage on the ADC side of C_2 turns to about 1/2 (V_{RT} + V_{RB}). To transfer DC elements of input signals, short C_2. At that time, it is necessary to bias input signals, but keeping R_2 open, Q_3 can also be used as buffer. Use the open space for the bias circuit.

5. Clamp pulse latch
   On the evaluation board, the clamp pulse is latched with ADC sampling CLK and then input to either PW pin or Sync pin. This is to minimize Vsag due the synchronizing of noise and clamp pulse beat elements with GND sampling clock around ADC. If there are no problems with Vsag, latch is not necessary.

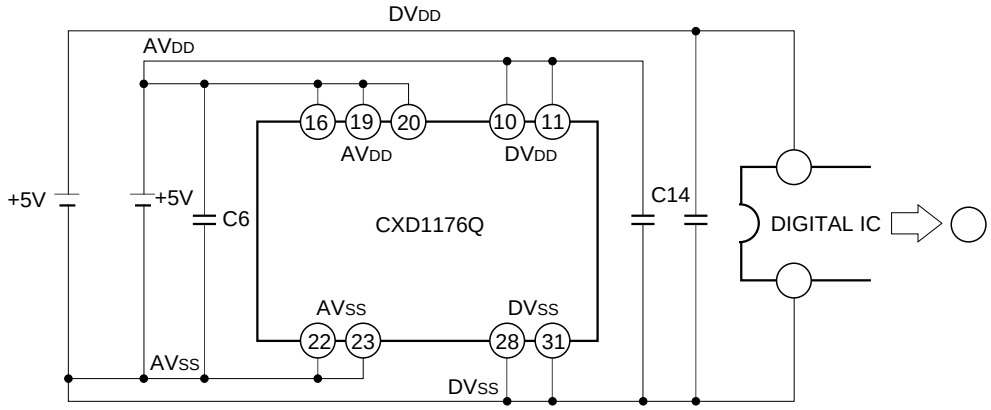
6. Peripheral through hole
   There is a group of through holes on the Analog input, output and Logic. There are to be used when mounting additional circuits to the PCB. Use when necessary.
   The connector hole on DAC part is used to mount the test chassis and the mount jack.

Latch Up Prevention

The CXD1176Q is a CMOS IC which requires latch up precautions. Latch up is mainly generated by the lag in the voltage rising time of AV_{DD} (Pins 16, 19 and 20) and DV_{DD} (Pin 10 and 11), when power supply is ON.

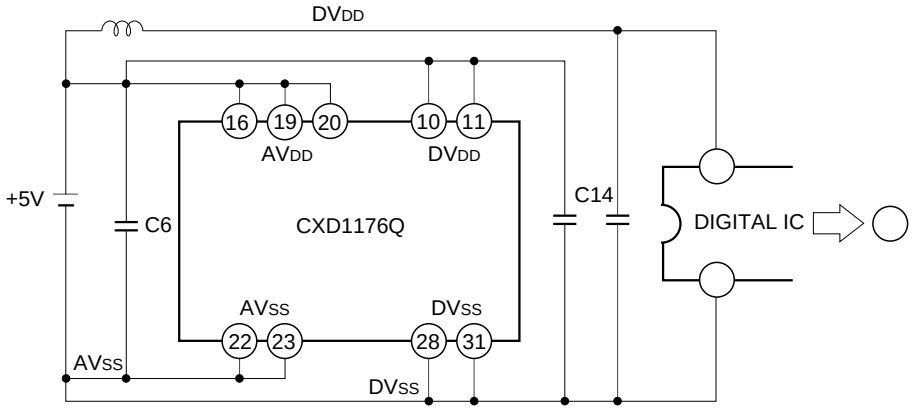
1. Correct usage

a. When analog and digital supplies are from different sources

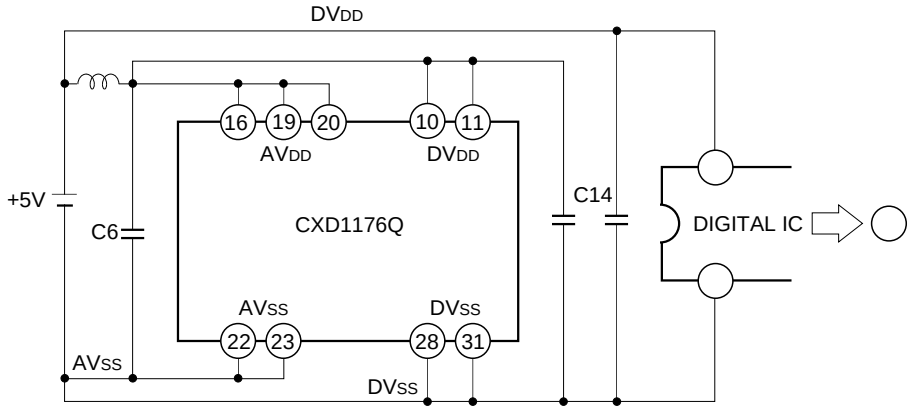


b. When analog and digital supplies are from a common source

(i)

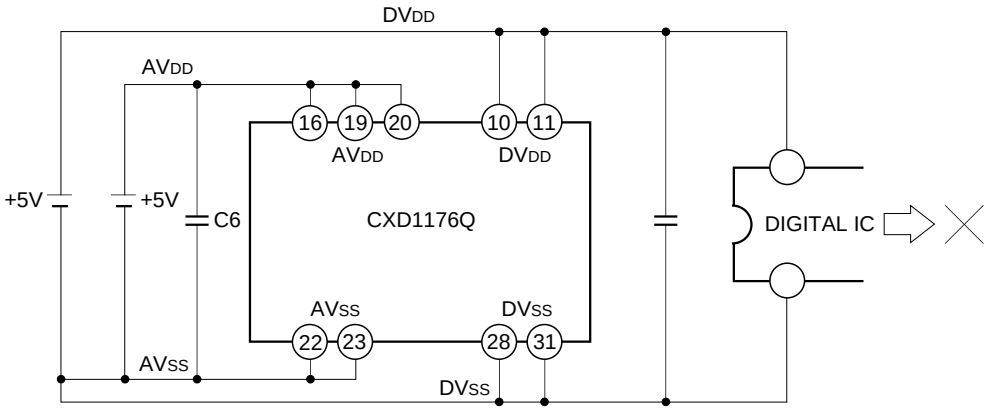


(ii)



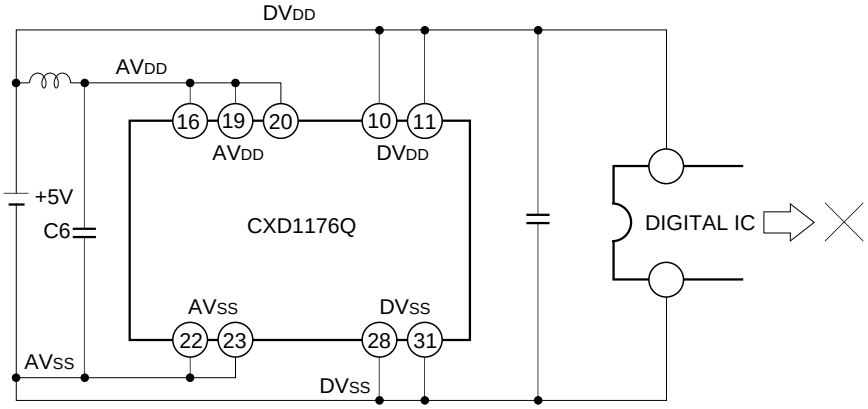
2. Example when latch up easily occurs

a. When analog and digital supplies are from different sources

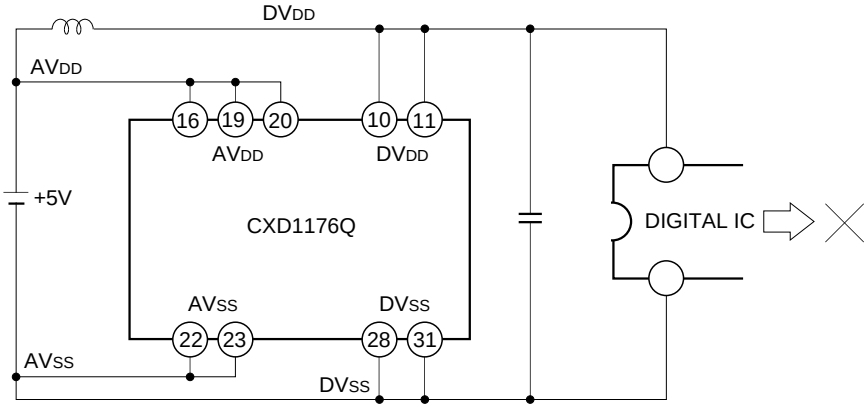


b. When analog and digital supplies are from a common source

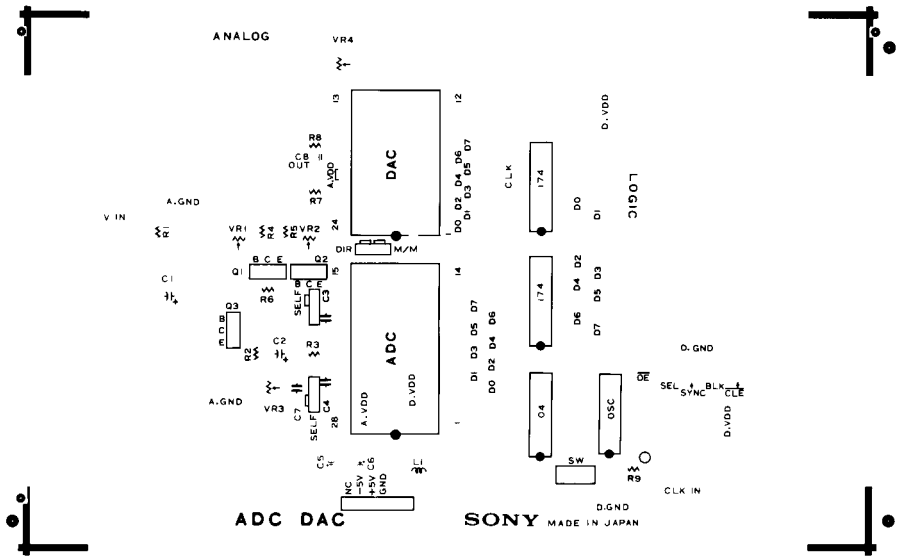
(i)



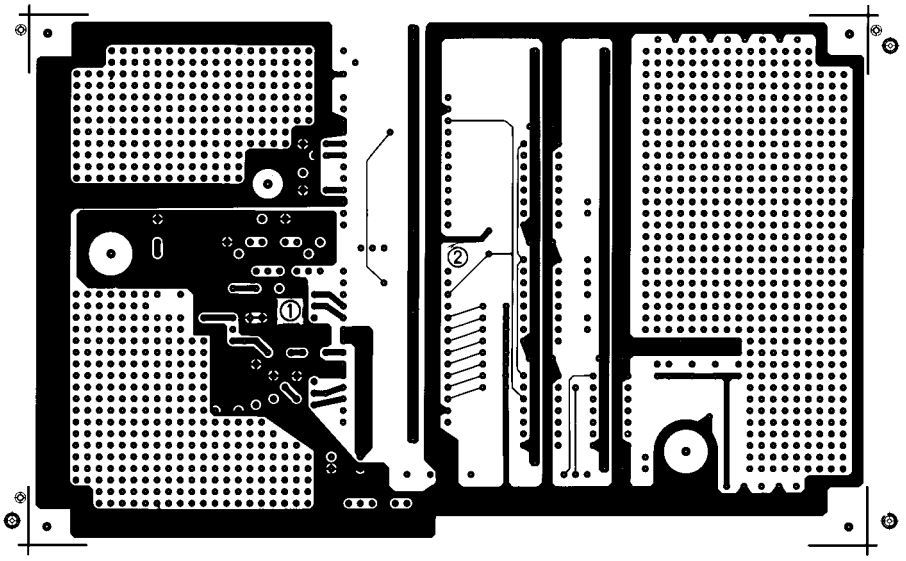
(ii)



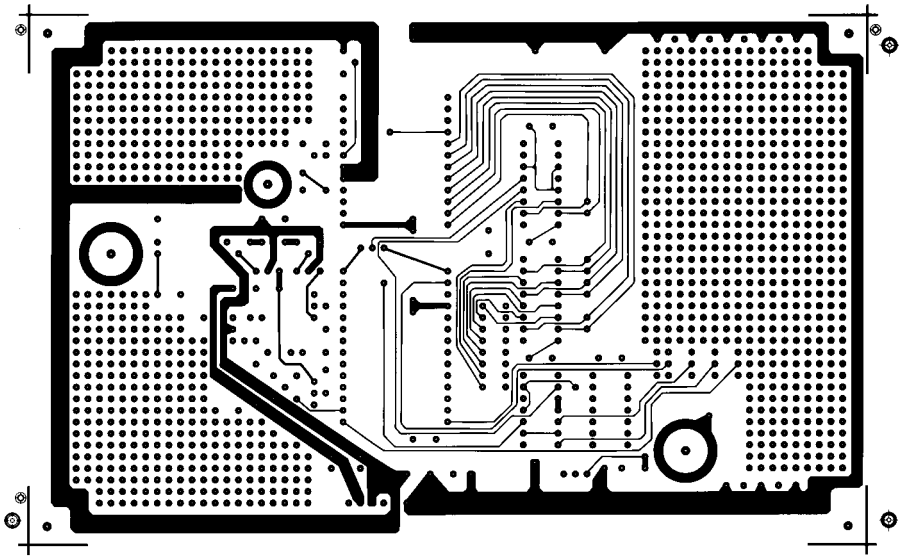
Silk Side



Component Side

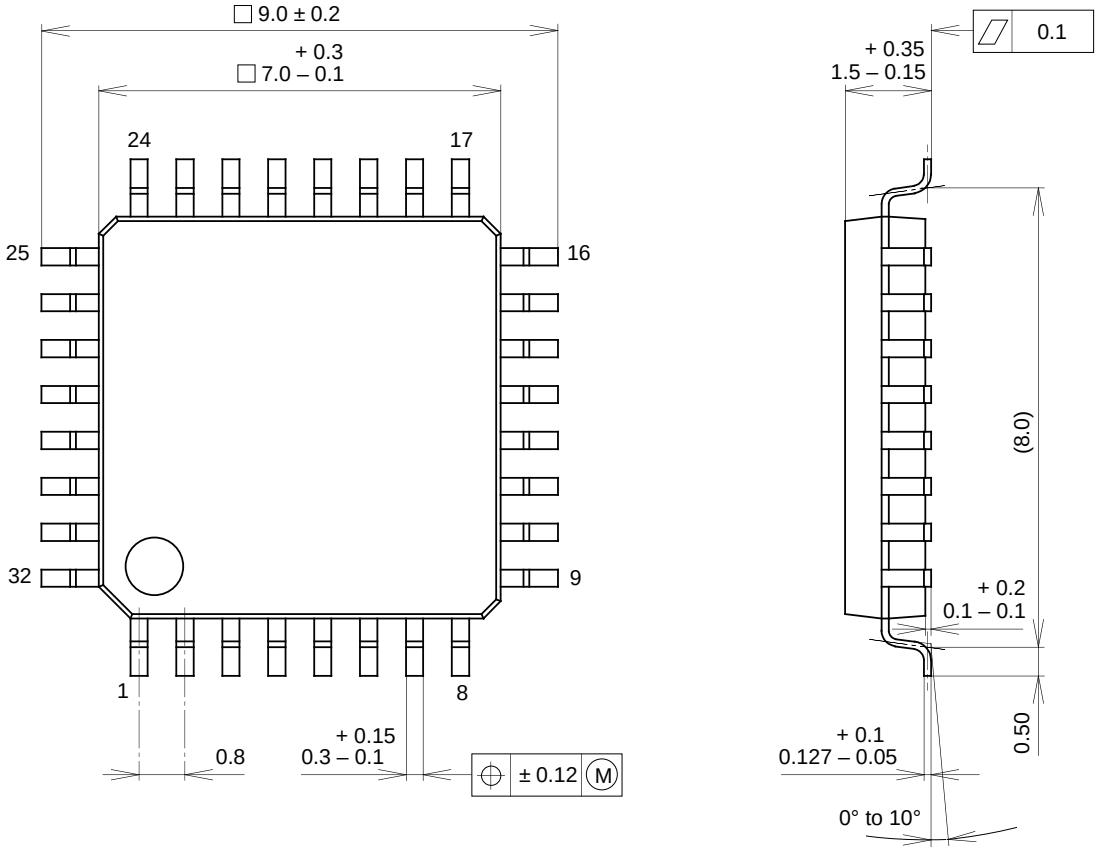


Soldering Side (Diagram seen from the component side)



Package Outline Unit: mm

32PIN QFP (PLASTIC)



SONY CODE	QFP-32P-L01
EIAJ CODE	*QFP032-P-0707-A
JEDEC CODE	————

PACKAGE MATERIAL	EPOXY RESIN
LEAD TREATMENT	SOLDER PLATING
LEAD MATERIAL	42 ALLOY
PACKAGE WEIGHT	0.2g